

Error Locating Driven Array*

Xintao Niu
State Key Laboratory for Novel
Software Technology
Nanjing University
China, 210023
niuxintao@gmail.com

Changhai Nie
State Key Laboratory for Novel
Software Technology
Nanjing University
China, 210023
changhainie@nju.edu.cn

JiaXi Xu
School of Mathematics and
Information Technology
Nanjing Xiaozhuang University
China, 211171
xujiaxi@126.com

ABSTRACT

Combinatorial testing(CT) seeks to handle potential faults caused by various interactions of factors that can influence the Software systems. When applying CT, it is a common practice to first generate a bunch of test cases to cover each possible interaction and then to locate the failure-inducing interaction if any failure is detected. Although this conventional procedure is simple and straightforward, we conjecture that it is not the ideal choice in practice. This is because 1) testers desires to isolate the root cause of failures before all the needed test cases are generated and executed 2) the early located failure-inducing interactions can guide the remaining test cases generation, such that many unnecessary and invalidate test cases can be avoided. For this, we propose a novel CT framework that allows for both generation and localization process to better share each other's information, as a result, both this two testing stages will be more effectively and efficiently when handling the testing tasks. We conducted a series of empirical studies on several open-source software, of which the result shows that our framework can locate the failure-inducing interactions more quickly than traditional approaches, while just needing less test cases.

Categories and Subject Descriptors

D.2.5 [Software Engineering]: Testing and debugging—*Debugging aids, testing tools*

General Terms

Reliability, Verification

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Keywords

Software Testing, Combinatorial Testing, Covering Array, Failure-inducing combinations

1. INTRODUCTION

Modern software is designed modular, platform-cross, language-cross and configurable. Although the sophisticated design can make the system more flexible and more powerful, it also makes the testing task a challenging work. This is because the candidate factors that can influence the system's behaviour, e.g., possible configuration options, system inputs, message events and the like, increases rapidly, and what's worse, the interactions between these factors can also crash the system, e.g., the compatibility problems. In consideration of the scale of the possible configurations, inputs, events, and their possible interactions (we call them the interactions space) of the real industrial software, to test all the possible combination of all the possible factors is not feasible, and even it is possible, it is also wasting as numerous interactions do not provide any useful information.

Empirical studies shows that the effective interaction space is not of small size. Cohen[] studies the , and find 70 100 can be. []Shows that to get a some coverage, only a small subset of all the configuration is needed. To this aim,

Typically, when applying CT in practice, there are four testing stages that should be cated as in figure. At the very early of the testing work, engineers should characterize which options and what inputs , i.e., to identify the factors and their possible values. This stage is labor-consuming, at least in the initial testing. The second stage is to generate a bunch of test cases to meet some criteria. In CT, the most common scenario is to cover all the iterations with the factors in the interactions no more than a prior fixed number t , in such way, the test suites of CT is also called the t -way covering array. The third testing stage is to fault localization, i.e., to isolate the failure-inducing interactions which owes to those failures triggered in those test cases in these test cases. The final stage is to evaluate the quality of the test cases.

This conventional CT framework is simple and straightforward, however, we conjecture, it is not he suitable choices and not the choices for most test engineers. The first, Second, and most importantly, is.

For this, we.

2. MOTIVATING EXAMPLE

Combinatorial testing can effectively detect the failures

caused by the interactions between various options or inputs of the SUT. Covering arrays, the test suite generated by this technique can cover each combination of the options at least once. We conjecture, however, although covering array can effectively, in practice, covering array was too much for detecting and locating the error in particular software.

As an motivating example, we looked through the following scenarios for detecting and locating the errors in the SUT.

Too much redundant fault test cases:

Too much redundant right test cases:

3. BACKGROUND

This section presents some definitions and propositions to give a formal model for the FCI problem.

3.1 Failure-inducing combinations in CT

Assume that the SUT is influenced by n parameters, and each parameter p_i has a_i discrete values from the finite set V_i , i.e., $a_i = |V_i|$ ($i = 1, 2, \dots, n$). Some of the definitions below are originally defined in .

Definition 1. A *test case* of the SUT is an array of n values, one for each parameter of the SUT, which is denoted as a n -tuple (v_1, v_2, \dots, v_n) , where $v_1 \in V_1, v_2 \in V_2 \dots v_n \in V_n$.

In practice, these parameters in the test case can represent many factors, such as input variables, run-time options, building options or various combination of them. We need to execute the SUT with these test cases to ensure the correctness of the behaviour of the software.

We consider the fact that the abnormally executing test cases as a *fault*. It can be a thrown exception, compilation error, assertion failure or constraint violation. When faults are triggered by some test cases, what is desired is to figure out the cause of these faults, and hence some subsets of this test case should be analysed.

Definition 2. For the SUT, the n -tuple $(-, v_{n_1}, \dots, v_{n_k}, \dots)$ is called a k -value *combination* ($0 < k \leq n$) when some k parameters have fixed values and the others can take on their respective allowable values, represented as “-”.

In effect a test case itself is a k -value *combination*, when $k = n$. Furthermore, if a test case contain a *combination*, i.e., every fixed value in the combination is in this test case, we say this test case *hits* the *combination*.

Definition 3. let c_l be a l -value combination, c_m be an m -value combination in SUT and $l < m$. If all the fixed parameter values in c_l are also in c_m , then c_m *subsumes* c_l . In this case we can also say that c_l is a *sub-combination* of c_m and c_m is a *parent-combination* of c_l , which can be denoted as $c_l \prec c_m$.

For example, in the motivation example section, the 2-value combination $(-, 4, 4, -)$ is a sub-combination of the 3-value combination $(-, 4, 4, 5)$, that is, $(-, 4, 4, -) \prec (-, 4, 4, 5)$.

Definition 4. If all test cases contain a combination, say c , trigger a particular fault, say F , then we call this combination c the *faulty combination* for F . Additionally, if none sub-combination of c is the *faulty combination* for F , we then call the combination c the *minimal faulty combination* for F (It is also called Minimal failure-causing schema(MFS) in).

In fact, MFS and *minimal faulty combinations* are identical to the failure-inducing combinations we discussed previously. Figuring it out can eliminate all details that are irrelevant for causing the failure and hence facilitate the debugging efforts.

4. ALGORITHMS

4.1 Description

4.2 A case study

5. EMPIRICAL STUDIES

5.1 The existence of

5.1.1 Study setup

5.1.2 Result and discussion

5.2 Performance of the traditional algorithms

5.2.1 Study setup

5.2.2 Result and discussion

5.3 Performance of our approach

5.3.1 Study setup

5.3.2 Result and discussion

5.4 Threats to validity

6. RELATED WORKS

7. CONCLUSIONS